	Based on Form PTO-1449 (3/90)				ATTY. DOCKET NO.		SERIAL NO. 10/621, 236 To be assigned			
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	LIST OF REFERENCES CITED BY APPLICANT  (Use several sheets if necessary)				APPLICANT					
•					Dr. Erwin HACKER, et al.					
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İ	EXAMINER INITIAL		DOCUMENT NUMBER	DATE		NAME	CLASS	SUBCLASS	FILING DATE IF APPROPRIATE	
	gu	AA	US 4,249,937	02/10/81	Iwatal	Iwataki et al.		/		
	SM	AB	US 4,422,864	12/27/83	Becker et al.					
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1	Vin	- AE	WO 99/57982	11/18/99	WIPO	)				
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	SMC	AG	EP 0 071 707 A1	02/16/83	EURC	PE				
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1	me	AL.	JP 52-112945 (and English equivalent U.S. Pat. No. 4,249,937 cited above)	09/21/77	JAPA	N				
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	• EXAMINER: citation if not in	Initial if refer	rence considered, whether or notes and not considered. Include copy	itation is in conform y of this form with r	nance with	MPEP 609. Draw line through mication to applicant.				